

**CLAIMS**

What is claimed is:

- 1    1.    Device for contacting and/or modifying a surface having a cantilever connected to  
2            an almost plane carrier element staying apart from said surface, said cantilever  
3            having a tip at its loose end being in close contact to said surface, wherein said  
4            cantilever stands out of the plane of said carrier element.
  
- 1    2.    Device according to claim 1, wherein said cantilever is bent along its direction.
  
- 1    3.    Device according to claim 1, wherein said cantilever is at least partially attached  
2            with additional material, said additional material having a thermal expansion  
3            coefficient  $c_1$ , which is different than the thermal expansion coefficient  $c_2$  of the  
4            material of which said cantilever is made.
  
- 1    4.    Device according to claim 3, wherein said additional material causes a defined  
2            stress moment acting onto said cantilever being bent through it out of the plane of  
3            said carrier element.
  
- 1    5.    Device according to claim 3, wherein said cantilever provides a base section  
2            which is fixed to said carrier element, onto said base section said additional

3 material is attached and extending into areas of said cantilever not being  
4 supported by said carrier element

1 6. Device according to claim 3, wherein said cantilever is made of silicon and said  
2 additional material is of silicon nitride.

1 7. Device according to claim 3, wherein said additional material is attached directly  
2 onto said cantilever as a layer defined by thickness and length.

1 8. Device according to claim 1, wherein the cantilever is made of a material or a  
2 material composition providing an intrinsic stress make the cantilever bending out  
3 of said plane.

1 9. Device according to claim 8, wherein said intrinsic stress is provided by a thermal  
2 treatment of said cantilever.

1 10. Device according to claim 8, wherein said intrinsic stress is provided by  
2 implantation in the cantilever.

1 11. Device according to claim 1, wherein said tip is directed approximately  
2 perpendicular towards said cantilever and protruding the surface of said  
3 cantilever.

- 1    12.    Device according to claim 1, wherein said tip is provided on a side of said  
2           cantilever being turned away from said surface and said cantilever being bent  
3           along its direction about approximately 180° so that said tip is in contact with said  
4           surface.
- 1    13.    Device according to claim 1, wherein said tip and the direction of said cantilever  
2           enclose an angle between 0° and 90°.
- 1    14.    Device according to claim 13, wherein said cantilever is bent along its direction  
2           about 90° maximally.
- 1    15.    Device according claim 1, wherein said tip is of the same or different material as  
2           that of the cantilever.
- 1    16.    Device according to claim 1, wherein said tip does not tower above the plane of  
2           said cantilever and is connected in one piece with said cantilever.
- 1    17.    Device according to claim 1, wherein said surface is a storage media, like a thin  
2           polymer film, into which thermomechanical writing and thermal readout of binary  
3           information takes place by said tip.
- 1    18.    Device according to claim 1, wherein said surface is a surface onto which  
2           lithographic and imaging techniques are applicable using said tip.

- 1 19. Device according to claim 1, wherein said surface is of a nature which is
- 2 modifiable by said tip.